

## Silicon N-Channel Power MOSFET

### Description

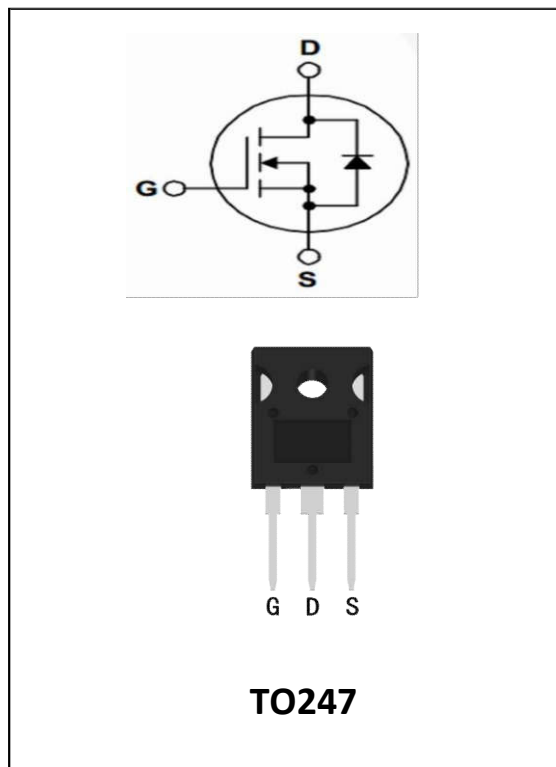
IRFP260N the silicon N-channel Enhanced MOSFETs, is obtained by advanced MOSFET technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor is suitable device for SMPS, high speed switching and general purpose applications.

### General Features

- ①  $V_{DS}=200V$ ,  $R_{ds(on)} < 50m\Omega$  @  $V_{GS}=10V$ ,  $I_D=50A$  (Typ:40m $\Omega$ )
- ② Fast switching
- ③ 100% avalanche tested
- ④ Improved dv/dt capability

### Application

- ① Switch Mode Power Supply (SMPS)
- ② Uninterruptible Power Supply (UPS)
- ③ Power Factor Correction (PFC)



### Package Marking And Ordering Information:

| Ordering Codes | Package | Product Code | Packing |
|----------------|---------|--------------|---------|
| IRFP260N       | TO-247  | IRFP260N     | Tube    |

### Absolute Maximum Ratings TC = 25°C, unless otherwise noted

| Parameter                                        | Symbol         | Value      | Unit |
|--------------------------------------------------|----------------|------------|------|
|                                                  |                | TO-247     |      |
| Drain-Source Voltage                             | $V_{DSS}$      | 200        | V    |
| Continuous Drain Current                         | $I_D$          | 50         | A    |
| Pulsed Drain Current(note2)                      | $I_{DM}$       | 200        | A    |
| Gate-Source Voltage                              | $V_{GSS}$      | $\pm 20$   | V    |
| Single Pulse Avalanche Energy (note2)            | $E_{AS}$       | 780        | mJ   |
| Avalanche Current (note1)                        | $I_{AR}$       | 39.5       | V/ns |
| Repetitive Avalanche Energy (note1)              | $E_{AR}$       | 468        | W    |
| Power Dissipation (TC = 25°C)                    | $P_D$          | 250        | W    |
| Operating Junction and Storage Temperature Range | $T_J, T_{stg}$ | -55 to 175 | °C   |

**Thermal Resistance**

| Parameter                               | Symbol     | Value  | Unit                        |
|-----------------------------------------|------------|--------|-----------------------------|
|                                         |            | TO-247 |                             |
| Thermal Resistance, Junction-to-Case    | $R_{thJC}$ | 0.5    | $^{\circ}\text{C}/\text{W}$ |
| Thermal Resistance, Junction-to-Ambient | $R_{thJA}$ | 45     |                             |

**Specifications  $T_J = 25^{\circ}\text{C}$ , unless otherwise noted**

| Parameter                          | Symbol        | Test Conditions                                                                             | Value |      |      | Unit             |
|------------------------------------|---------------|---------------------------------------------------------------------------------------------|-------|------|------|------------------|
|                                    |               |                                                                                             | Min.  | Typ. | Max. |                  |
| Drain-Source Breakdown Voltage     | $V_{(BR)DSS}$ | $V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$                                                  | 200   | --   | --   | V                |
| Zero Gate Voltage Drain Current    | $I_{DSS}$     | $V_{DS} = 200\text{V}, V_{GS} = 0\text{V}, T_J = 25^{\circ}\text{C}$                        | --    | --   | 1    | $\mu\text{A}$    |
| Gate-Source Leakage                | $I_{GSS}$     | $V_{GS} = +20\text{V}, V_{DS} = 0\text{V}$                                                  | --    | --   | 100  | nA               |
|                                    |               | $V_{GS} = -20\text{V}, V_{DS} = 0\text{V}$                                                  | --    | --   | -100 |                  |
| Gate-Source Threshold Voltage      | $V_{GS(th)}$  | $V_{DS} = V_{GS}, I_D = 250\mu\text{A}$                                                     | 2.0   | --   | 4.0  | V                |
| Drain-Source On-Resistance (Note3) | $R_{DS(on)}$  | $V_{GS} = 10\text{V}, I_D = 25\text{A}$                                                     | --    | 40   | 50   | $\text{m}\Omega$ |
| Input Capacitance                  | $C_{iss}$     | $V_{GS} = 0\text{V},$<br>$V_{DS} = 25\text{V},$<br>$f = 1.0\text{MHz}$                      | --    | 3538 | --   | pF               |
| Output Capacitance                 | $C_{oss}$     |                                                                                             | --    | 657  | --   |                  |
| Reverse Transfer Capacitance       | $C_{rss}$     |                                                                                             | --    | 280  | --   |                  |
| Total Gate Charge                  | $Q_g$         | $V_{DD} = 160\text{V},$<br>$I_D = 25\text{A},$<br>$V_{GS} = 0 \text{ to } 10\text{V}$       | --    | 244  | --   | nC               |
| Gate-Source Charge                 | $Q_{gs}$      |                                                                                             | --    | 16   | --   |                  |
| Gate-Drain Charge                  | $Q_{gd}$      |                                                                                             | --    | 144  | --   |                  |
| Turn-on Delay Time                 | $t_{d(on)}$   | $V_{DD} = 100\text{V},$<br>$I_D = 25\text{A},$<br>$V_{GS} = 10\text{V}$<br>$R_G = 25\Omega$ | --    | 53   | --   | ns               |
| Turn-on Rise Time                  | $t_r$         |                                                                                             | --    | 65   | --   |                  |
| Turn-off Delay Time                | $t_{d(off)}$  |                                                                                             | --    | 689  | --   |                  |
| Turn-off Fall Time                 | $t_f$         |                                                                                             | --    | 230  | --   |                  |
| Continuous Body Diode Current      | $I_S$         | $T_C = 25^{\circ}\text{C}$                                                                  | --    | --   | 50   | A                |
| Pulsed Diode Forward Current       | $I_{SM}$      |                                                                                             | --    | --   | 200  |                  |
| Body Diode Voltage                 | $V_{SD}$      | $T_J = 25^{\circ}\text{C}, I_{SD} = 25\text{A}, V_{GS} = 0\text{V}$                         | --    | --   | 1.5  | V                |
| Reverse Recovery Time              | $t_{rr}$      | $V_{GS} = 0\text{V}, I_S = 25\text{A},$<br>$dI_F/dt = 100\text{A}/\mu\text{s}$              | --    | 208  | --   | ns               |
| Reverse Recovery Charge            | $Q_{rr}$      |                                                                                             | --    | 2.04 | --   | $\mu\text{C}$    |

**Notes**

1.Repetitive Rating: Pulse width limited by maximum junctiontemperature

 2. $I_{AS} = 30\text{A}, V_{DD} = 30\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^{\circ}\text{C}$ 

 Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 1\%$

Typical Characteristics  $T_J = 25^\circ\text{C}$ , unless otherwise noted

Figure 1. Output Characteristics ( $T_J = 25^\circ\text{C}$ )

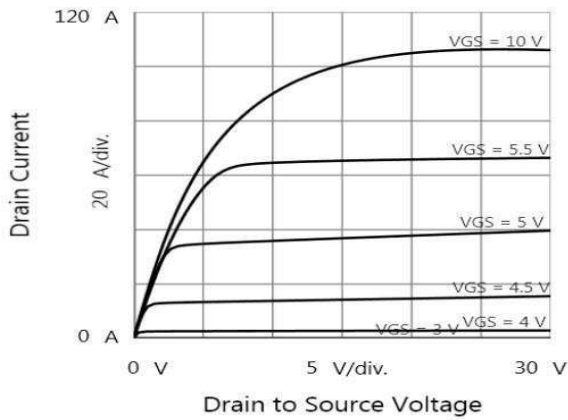


Figure 2. Transfer Characteristics

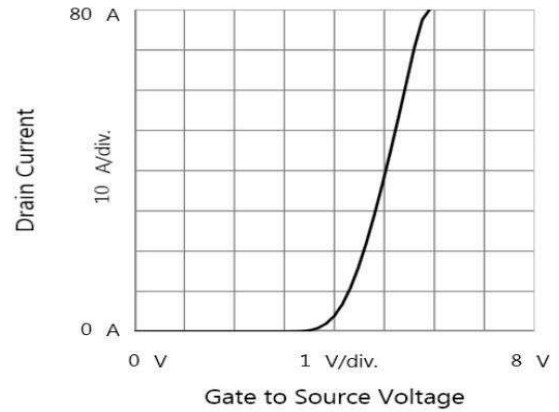


Figure 3. Maximum Continuous Drain Current vs Case Temperature

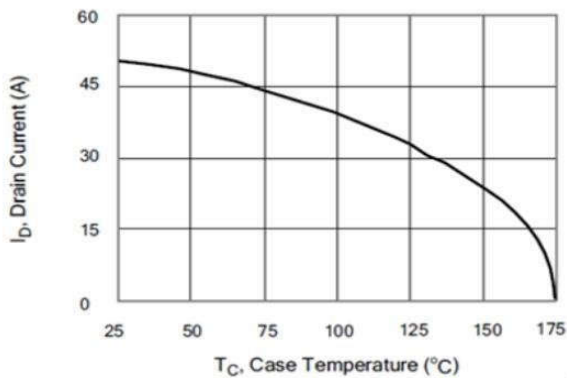


Figure 4. Drain to Source Voltage vs. Gate to Source Voltage

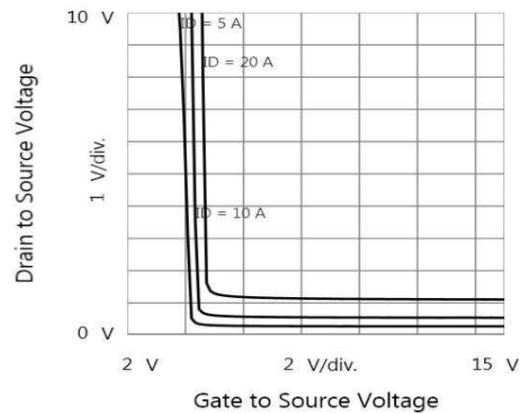


Figure 5. Typical Breakdown Voltage vs Junction Temperature

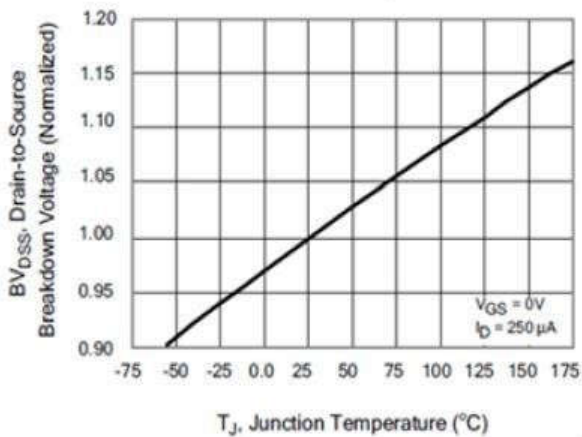
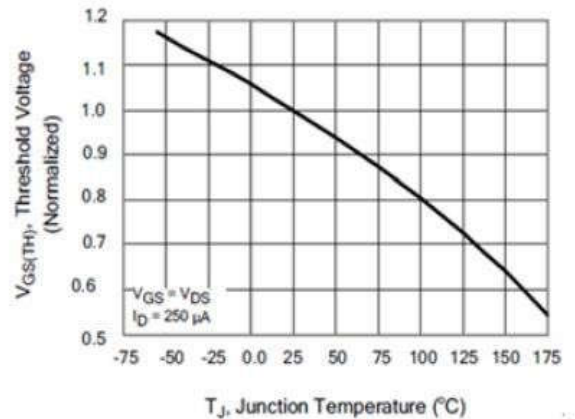
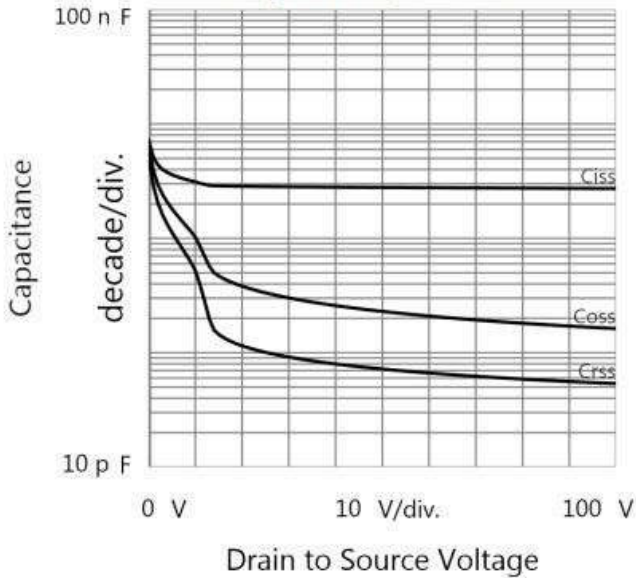


Figure 6. Typical Threshold Voltage vs Junction Temperature

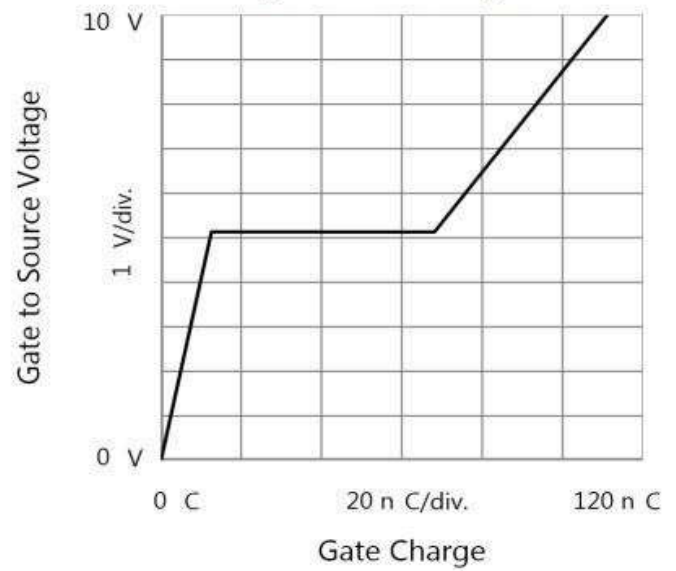


Typical Characteristics  $T_J = 25^\circ\text{C}$ , unless otherwise noted

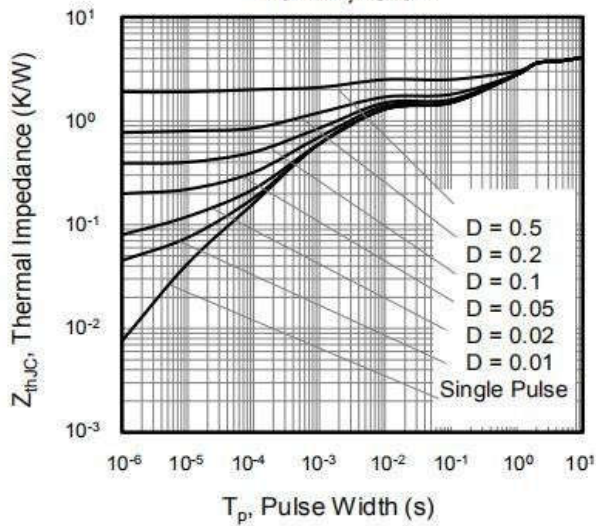
**Figure 7. Capacitance**



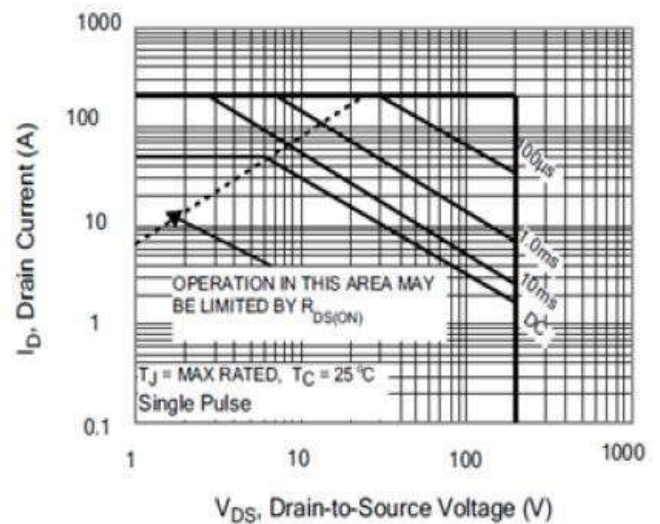
**Figure 8. Gate Charge**



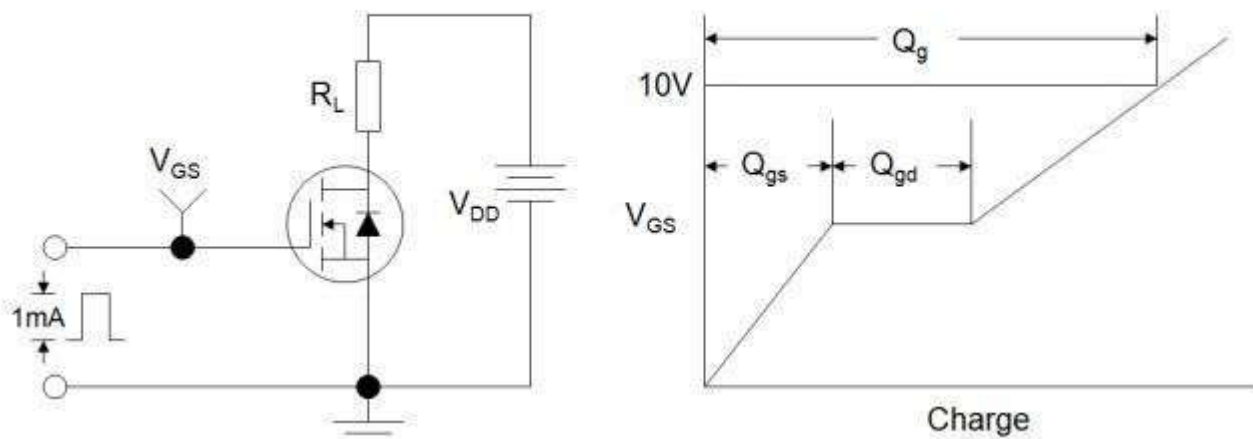
**Figure 9. Transient Thermal Impedance  
TO-247, TO-3P**



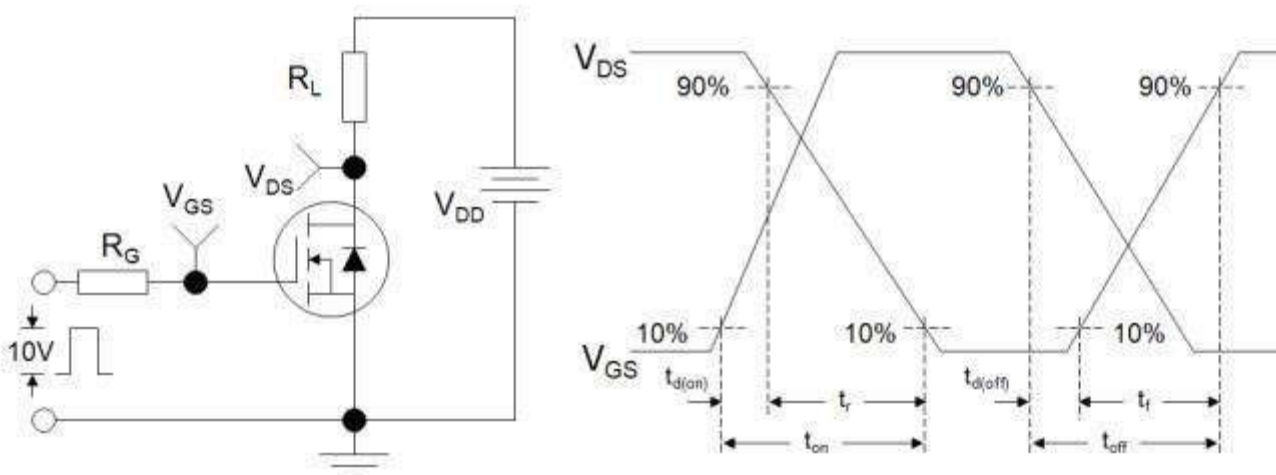
**Figure 10. Maximum Forward Bias Safe  
Operating Area**



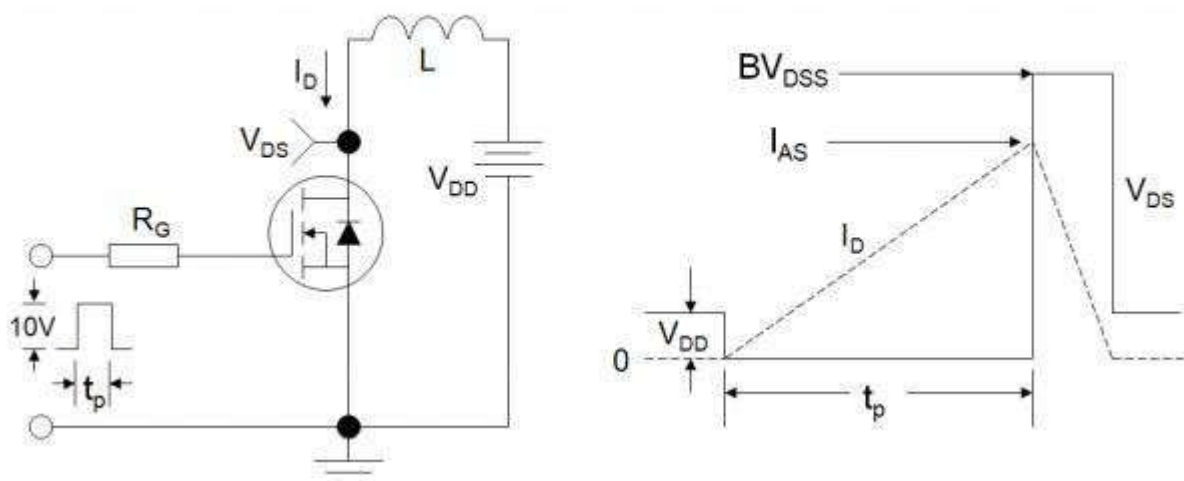
**Figure A: Gate Charge Test Circuit and Waveform**



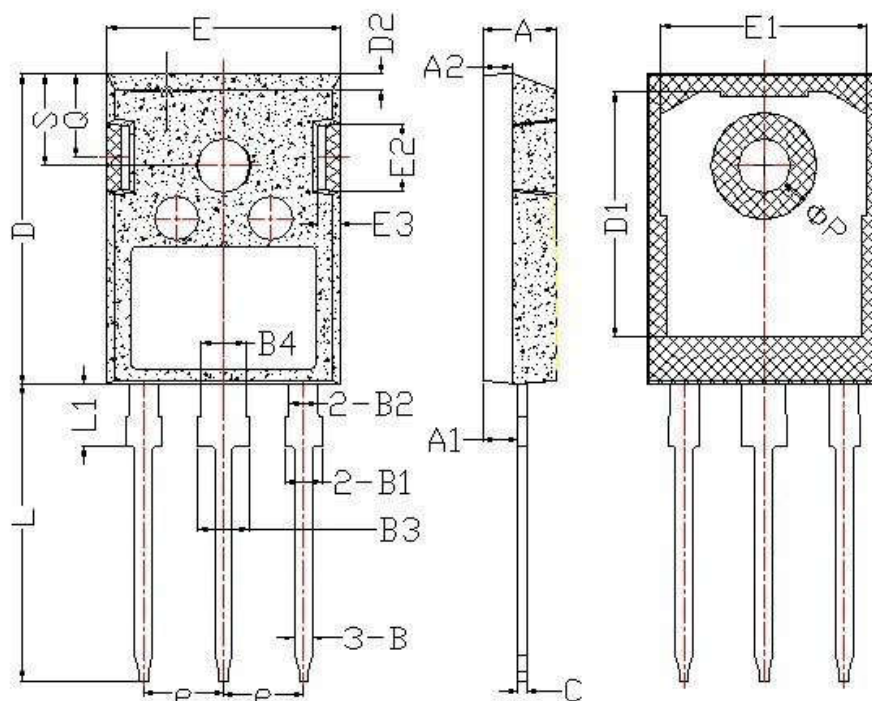
**Figure B: Resistive Switching Test Circuit and Waveform**



**Figure C: Unclamped Inductive Switching Test Circuit and Waveform**



## Package Description



| Items | Values(mm) |       |
|-------|------------|-------|
|       | MIN        | MAX   |
| A     | 4.6        | 5.2   |
| A1    | 2.2        | 2.6   |
| B     | 0.9        | 1.4   |
| B1    | 1.75       | 2.35  |
| B2    | 1.75       | 2.15  |
| B3    | 2.8        | 3.35  |
| B4    | 2.8        | 3.15  |
| C     | 0.5        | 0.7   |
| D     | 20.60      | 21.30 |
| D1    | 16         | 18    |
| E     | 15.5       | 16.10 |
| E1    | 13         | 14.7  |
| E2    | 3.80       | 5.3   |
| E3    | 0.8        | 2.60  |
| e     | 5.2        | 5.7   |
| L     | 19         | 20.5  |
| L1    | 3.9        | 4.6   |
| ΦP    | 2.5        | 3.70  |
| Q     | 5.2        | 6.00  |
| S     | 5.8        | 6.6   |

TO-247 Package

[www.mns-kx.com](http://www.mns-kx.com)



迈诺斯科技

**IRFP260N**

**NOTE:**

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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